

DATA SHEET

Model MGFS804812

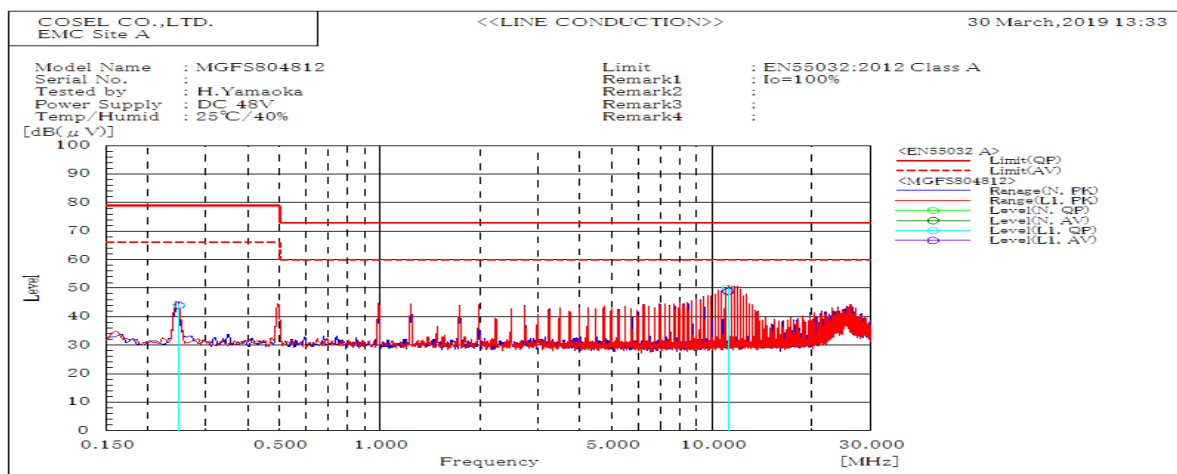
Date 23-Apr-19

Test EMI
Line conduction & Radiated emission

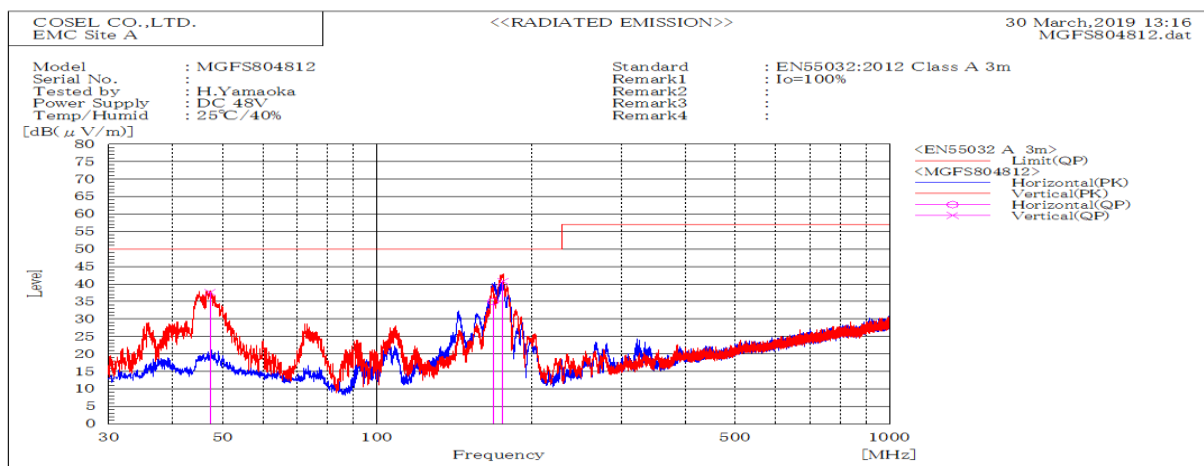
Temp. 25 degreeC

Humid. 40 %RH

Tested by H.Yamaoka



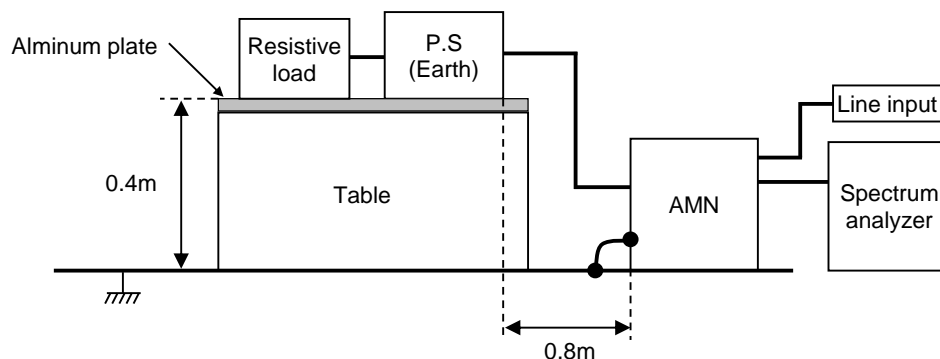
Frequency	Line	Level	Limit	Margin	Pass/Fail	Remark
MHz		dB(μV)	dB(μV)	dB		
		QP	AV	QP	AV	
11.173	L1	50	48.9	73	60	23
0.248	L1	44.2	44	79	66	34.8
11.163	N	50	48.9	73	60	23



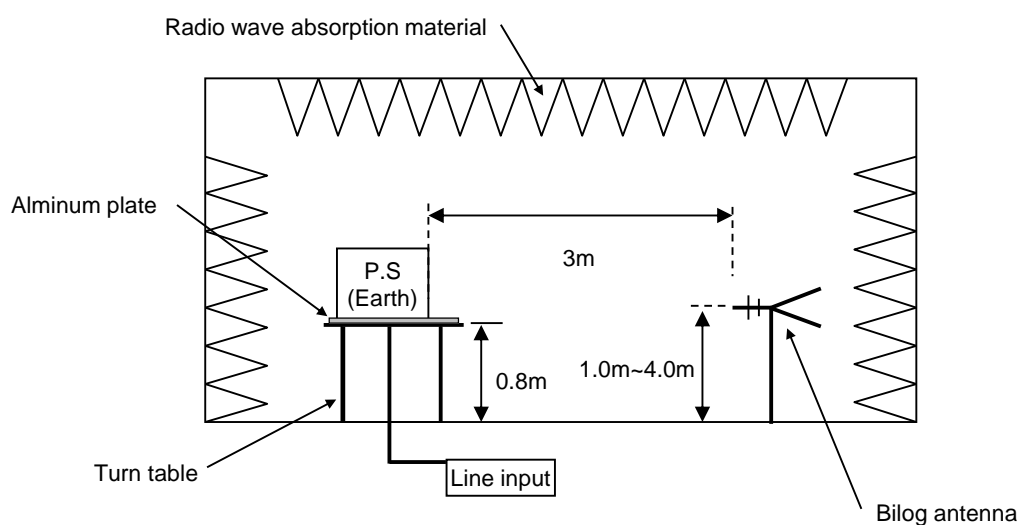
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
176.162	V	Stable	40.7	50	9.3	Pass	103.3	216	
47.317	V	Stable	37.6	50	12.4	Pass	100	1.7	
168.51	H	Stable	35	50	15	Pass	162.3	190.2	

DATA SHEET		Date	23-Apr-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

1. Line conduction



2. Radiated emission



Conditions

Test : EMI

Model Name : MGFS80□□

○Photographs of Test Set-Up LINE CONDUCTION



○Testing circuitry

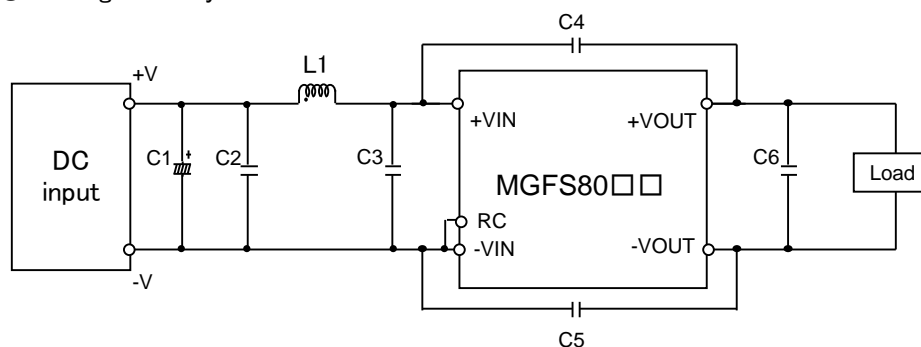


Fig.1 Testing circuitry

- C1 : MGFS8024□□ 63V 470 μ F Electrolytic capacitor (ELXZseries NIPPON CHEMI-CON)
MGFS8048□□ 100V 220 μ F Electrolytic capacitor (KYseries NIPPON CHEMI-CON)
- C2 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C3 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C4,C5 : MGFS8024□□ 2kV 2200pF Ceramic capacitor
(GR443QR73D222KW01 MURATA MANUFACTURING)
MGFS8048□□ 2kV 3300pF Ceramic capacitor
(GR443QR73D332KW01 MURATA MANUFACTURING)
- C6 : MGFS8024□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
MGFS8048□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
- L1 : MGFS8024□□ 12.0A 1.8 μ H Inductor (SRP7050TA-1R8M BOURNS)
MGFS8048□□ 8.0A 3.3 μ H Inductor (SRP7050TA-3R3M BOURNS)